

Application No.	ion No. Applicant(s)	
10/017,833	SOLHEIM ET AL.	
Examiner	Art Unit	
David C. Payne	2633	

SEARCHED				
Class	Subclass	Date	Examiner	
359	110	3/2/05	DCP	
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INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
East See Search Notes, IEEE Non-Patent Literature Database	3/2/2005	dcp		